Chip Scale Review

2016 Editorial Calendar

(Editorial close date: 11/20)	January • February	(* denotes show distribution)
Packaging trends		SEMI European 3D Summit Grenoble, France (Jan 18-20) * SMTA Pan Pac Microelectronics Symposium * Kohala Coast, Hawaii (Jan 25-28) SEMICON Korea Seoul, Korea (January 27-29) BiTS Workshop * Mesa, AZ (March 6-9) APEX Expo Las Vegas, NV (March 15-17) IMAPS Device Packaging (DPC) * Fountain Hills, AZ (March 15-17) SEMICON China* Productronica China Shanghai China (March 15-17)
Assembly materials		
Cu TSV stress analysis		
Wafer carrier solutions		
Recent advances in 3D package reliability		
Metrology for 3D integration		
Silicon photonics packaging		
Advances in wafer probing		
Socket contact technologies		

International Directory of Test and Burn-in Socket Suppliers

Ad Space Close Jan 22 - Ad Materials Deadline Jan 29

(Editorial close date: 2/5)	March • April	
MEMS in IoT devices		SEMICON South East Asia Penang, Malaysia (Apr 26-28)
Copper Pillar Technology		MEPTEC MEMS Symposium * San Jose, CA (May 11) • ECTC * Las Vegas, NV (May 31- June 3)
FOWLP		
Die-to-wafer stacking		
Flexible substrates		
Packaging of high-power devices		
3D integration in packaging		
Lithography for TSVs		
TSV technologies		

Ad Space Close Feb 19 - Materials Close Feb 26

(Editorial close date: 3/11)	May ∙ June	
Packaging trends & update		• IEEE/SW Test Workshop (SWTW) San Diego, CA (June 5-8)
Impact of wafer-based packaging on the supply chain		• Sensors Expo San Jose, CA (June 21-23)
FOWLP advances		SEMICON West * San Francisco, CA (July 12-14)
Improving yield & reliability in AOI		
Final test solution for WLCSP devices		
Multi-die assembled packages		
3D backside processing		
Emerging automotive applications		
Current state & evolving trends in MEMS packaging		

Ad Space Close May 20 - Ad Materials Close May 27